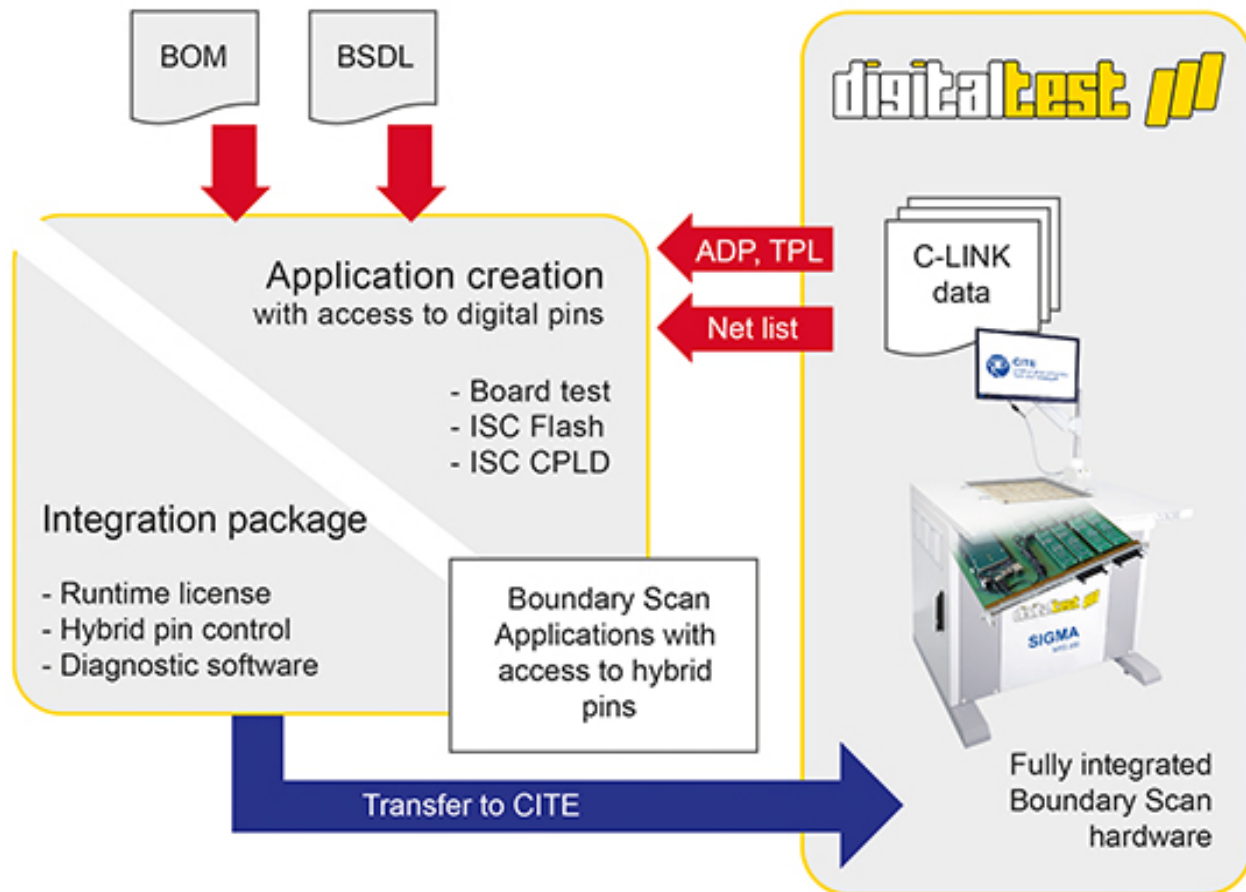


Boundary Scan for In-Circuit-Test



With our boundary scan upgrade for In-Circuit Tests (ICT) you can get the best of both testing methods worlds and achieve an optimal test strategy with maximum test coverage and reduced overall costs.

- > Reduces fixture costs by saving test points
- > Just one test fixture needed for boundary scan and ICT
- > Increases test coverage by integrating all test channels
- > Short test times by integrating with Digitaltest hybrid cards
- > Incorporates all functions in CITE - production remains in the familiar user Interface
- > Simple data export with C-LINK DTM for boundary scan software

Our main partners in matters of JTAG/Boundary Scan integration are the respected GÖPEL electronic and JTAG Technologies.